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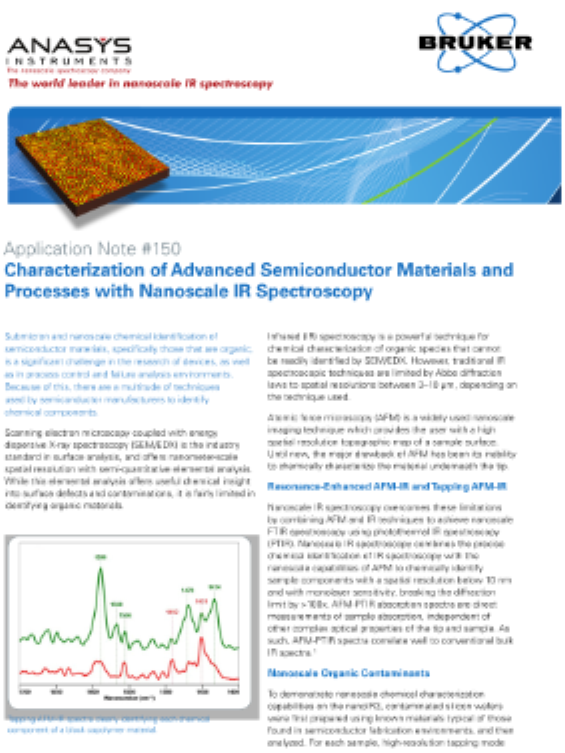
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Application Note #150
Characterization of Advanced Semiconductor Materials and Processes with Nanoscale IR Spectroscopy

Characterization of Advanced Semiconductor Materials and Processes with Nanoscale IR Spectroscopy

This application note demonstrates the successful application of Tapping AFM-IR to distinguish the chemical footprints of several nanoscale lithographic patterns consisting of complex molecular assemblies with excellent spatial resolution of 4 nm. Additionally, nanoscale IR spectroscopy also excels in the characterization of nanoscale defects.

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